



*Electronic Design Automation Laboratory*

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# An Efficient Bottom-Up Extraction Approach to Build the Behavioral Model of Switched-Capacitor $\Delta\Sigma$ Modulator

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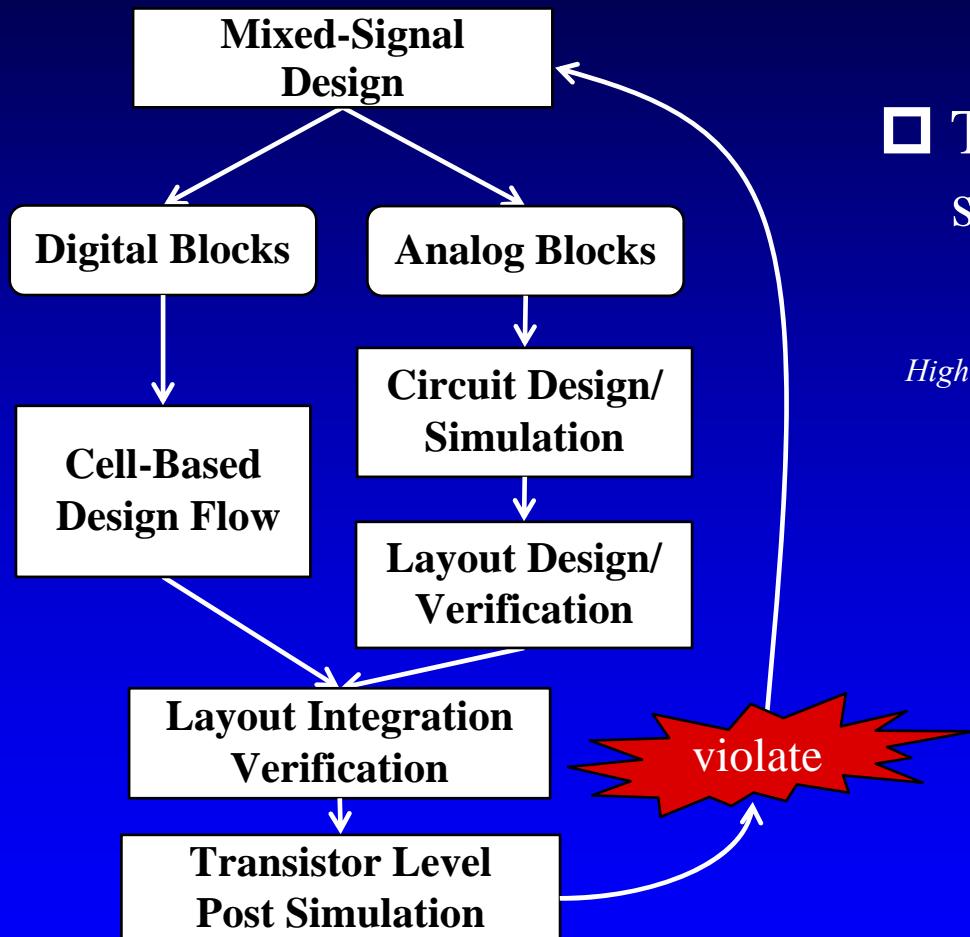


# Outline

- Introduction
- Second-Order Delta-Sigma ( $\Delta\Sigma$ ) Modulator
- Our Bottom-Up Extraction Flow for Non-Ideal Effects
- Experimental Results
- Conclusions

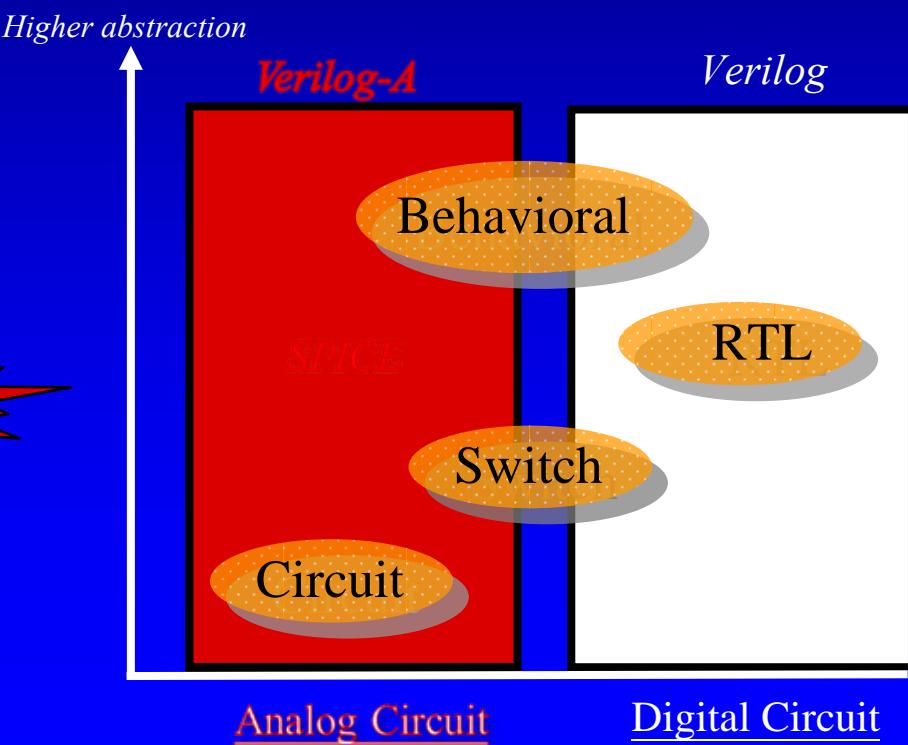


# Introduction



## Conventional MS Design Flow

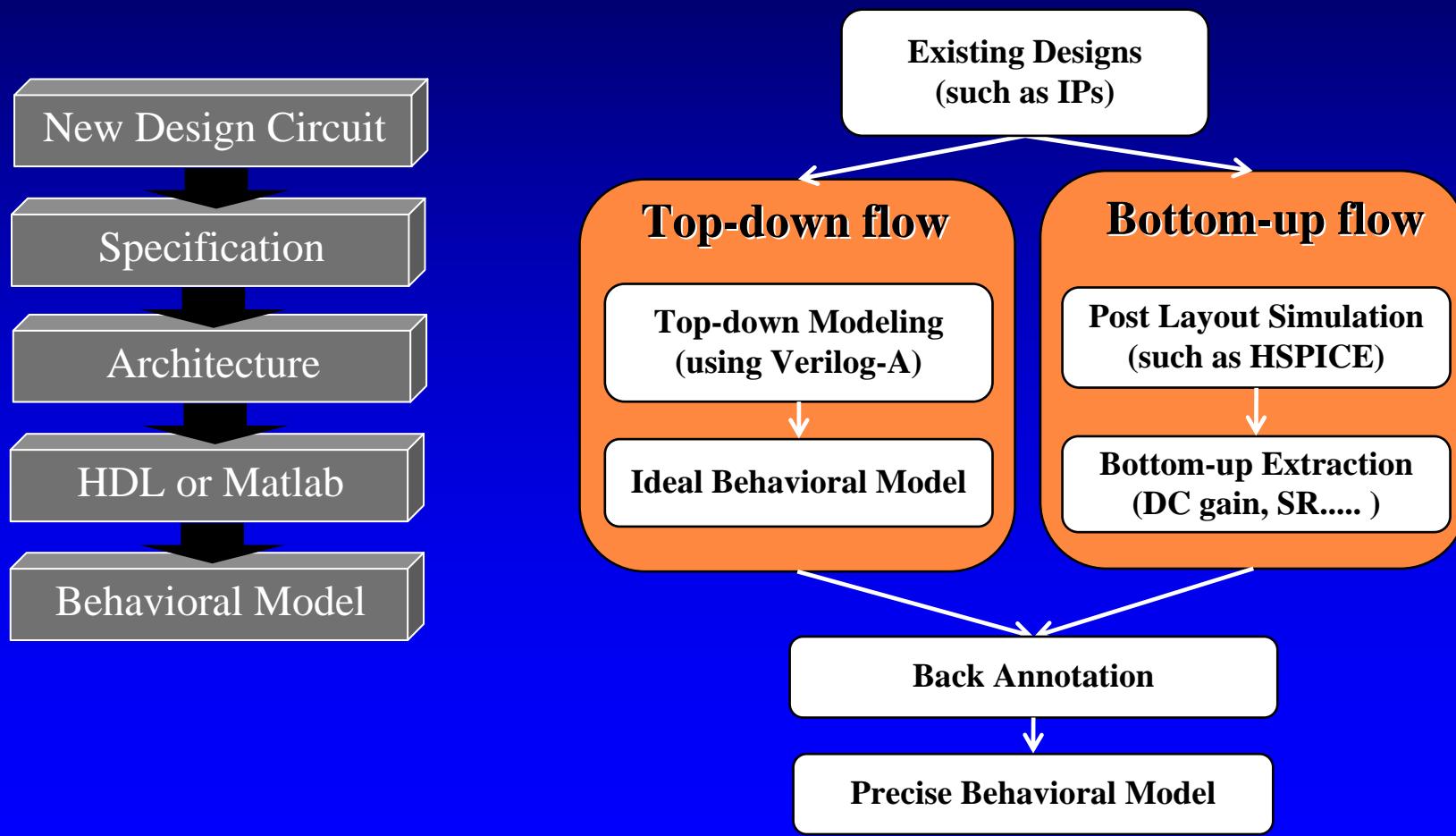
- Reduce iteration times
  - Reuse design and IP-Based design
- Transistor-level simulation is too slow
  - Behavior-level simulation





# Our Bottom-Up Modeling Flow

- Top-Down Behavior Modeling
  - Not Suitable for IP designs
- Our Modeling flow
  - Suitable for IP designs





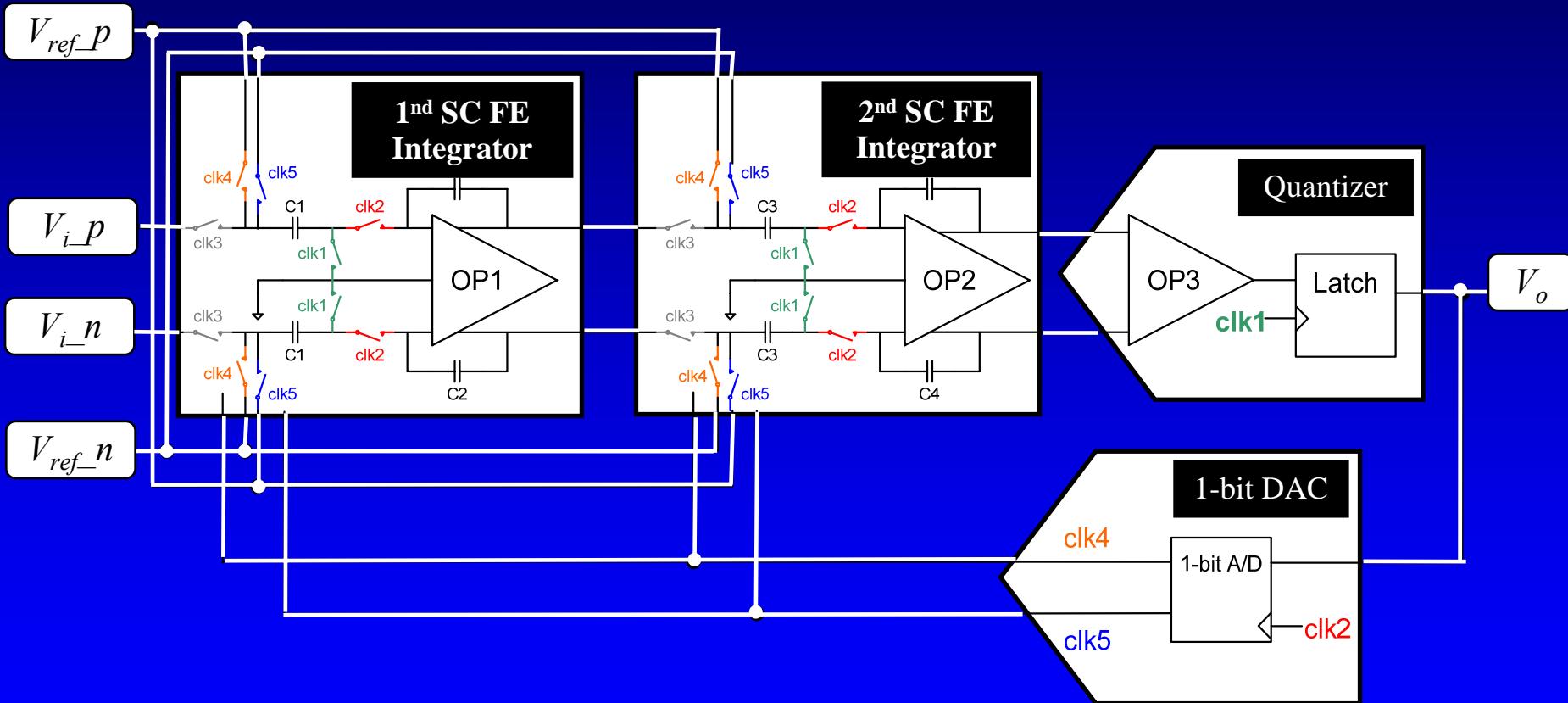
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- Introduction
- Second-Order Delta-Sigma ( $\Delta\Sigma$ ) Modulator
  - Top-down Ideal Behavioral Model
- Our Bottom-Up Extraction Flow for Non-Ideal Effects
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# Second-Order SC $\Delta\Sigma$ Modulator

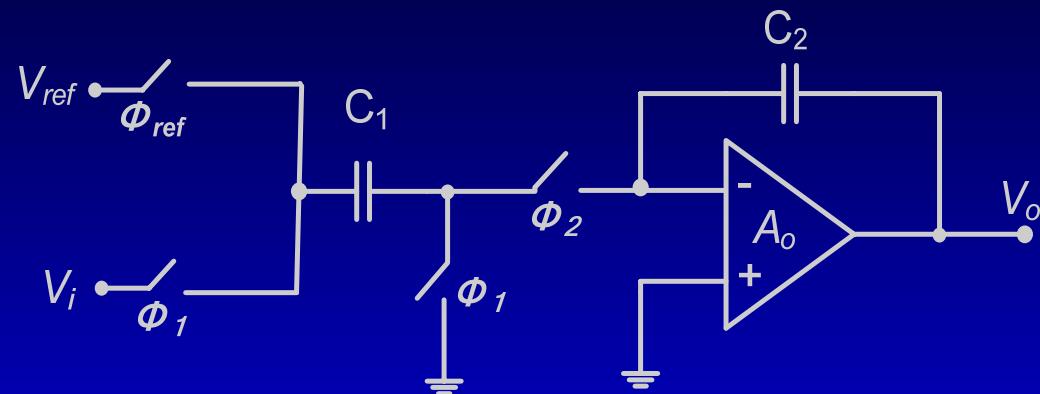
- Five clock signals to control this operation





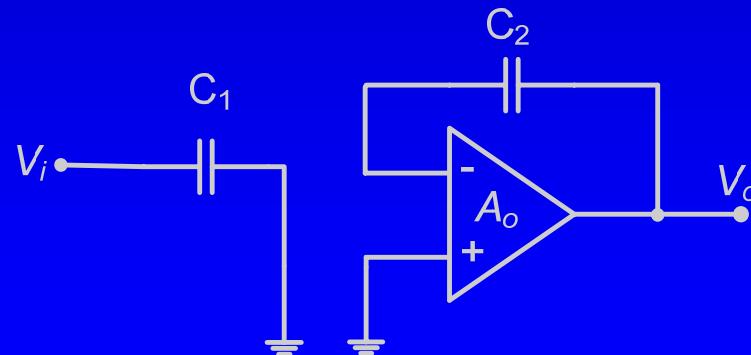
# SC FE Integrator

## □ Architecture



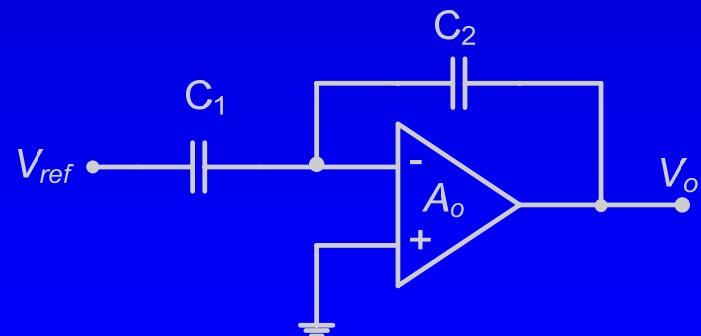
## □ Sampling mode

- $\Phi_1$  on ;  $\Phi_2$ ,  $\Phi_{ref}$  off



## □ Integration mode

- $\Phi_1$  off ;  $\Phi_2$ ,  $\Phi_{ref}$  on

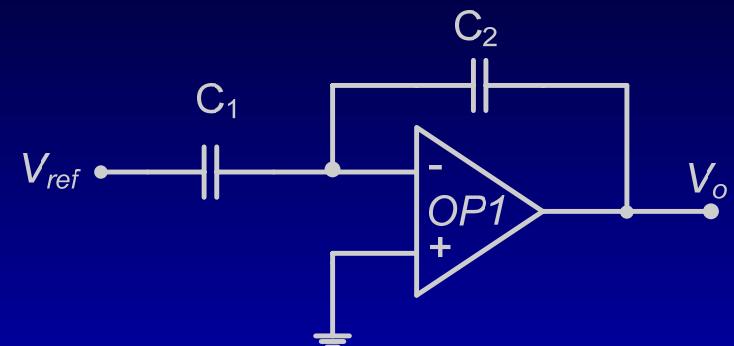




# Ideal Behavioral Model

## □ SC Integrator

- Integration mode



## □ Time-domain transfer function

$$\text{➤ } C_1 \cdot V_i^o(t_n) - C_1 \cdot V_{ref}^e(t_n + \frac{T}{2}) = C_2 \cdot [V_i^e(t_n + \frac{T}{2}) - V_i^o(t_n)]$$

$$C_1 \cdot V_i^e(t_n + \frac{T}{2}) - C_1 \cdot V_{ref}^e(t_n + \frac{T}{2}) = C_2 \cdot [V_i^e(t_n + \frac{T}{2}) - V_i^e(t_n - \frac{T}{2})]$$

## □ Z-domain transfer function

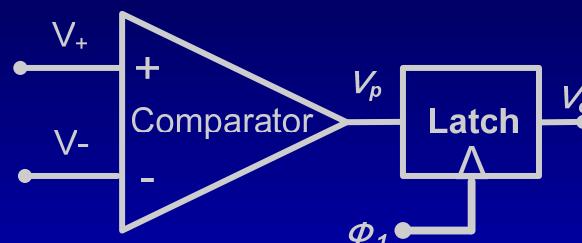
$$\text{➤ } C_1 V_i^e(z) - C_1 V_{ref}^e(z) = C_2 (1 - z^{-1}) V_i^e(z)$$

$$V_i^e(z) = \frac{C_1}{C_2} \frac{1}{1 - z^{-1}} [V_{in}^e(z) - V_{out}^e(z)]$$

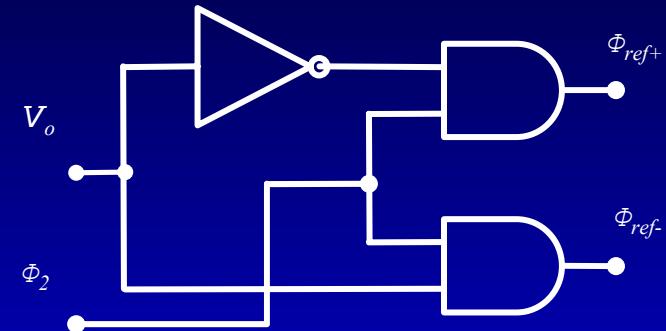


# Other Circuit Blocks

## □ Quantizer



## □ 1-bit DAC



## □ Circuit behavior

### Comparator

If  $V_+ > V_-$ ,  $V_p = V_H$ ,  
else  $V_p = V_L$

### Latch

If  $\Phi_1$  on,  $V_o = V_p$ ,  
else  $V_o = V_o$

If  $\Phi_2$  on,  $\Phi_{ref+} = \sim V_o$ ,  $\Phi_{ref-} = V_o$   
else  $\Phi_{ref+} = 0$ ,  $\Phi_{ref-} = 0$



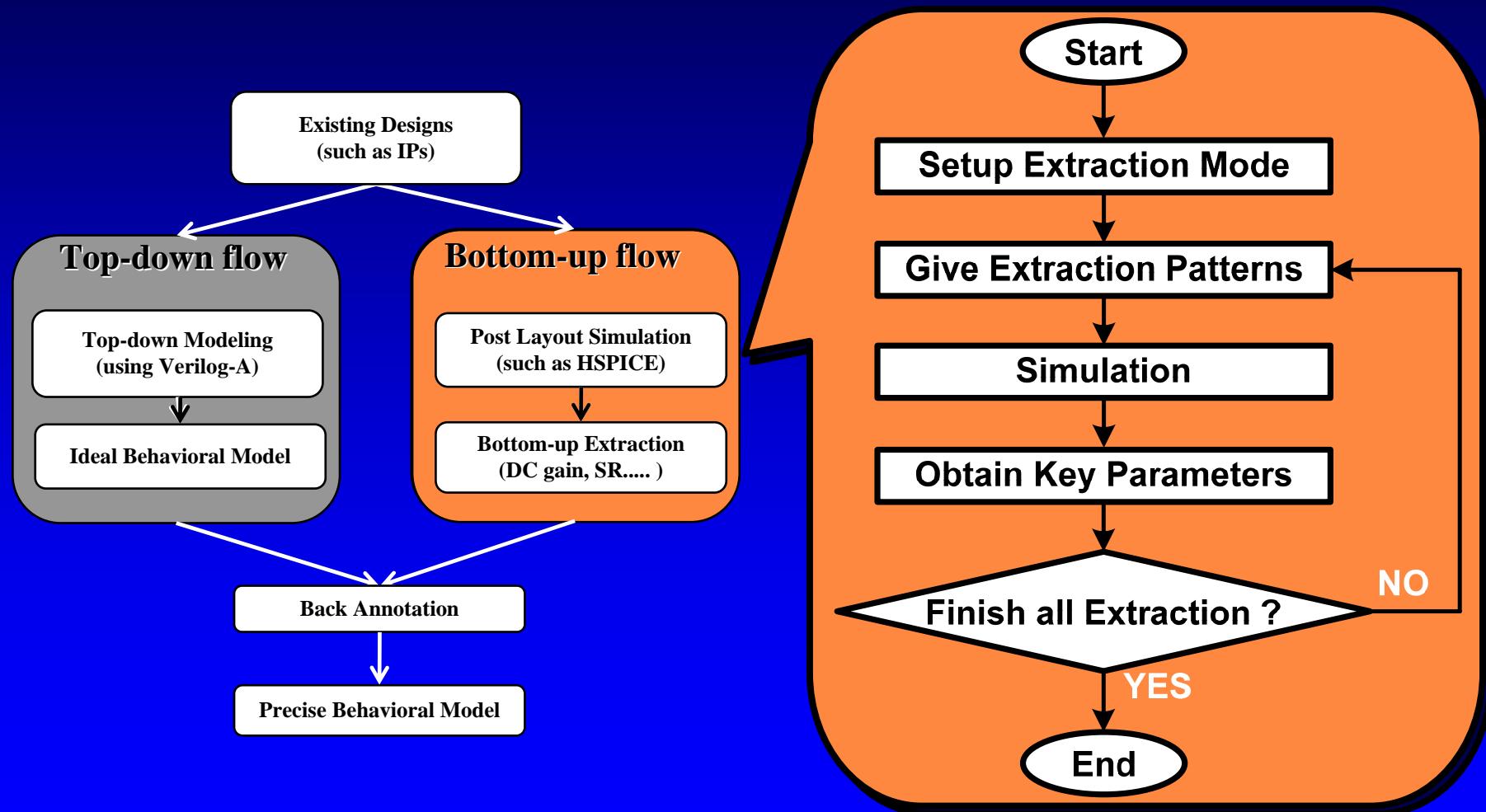
# Outline

- Introduction
- Second-Order Delta-Sigma ( $\Delta\Sigma$ ) Modulator
- Our Bottom-Up Extraction Flow for Non-Ideal Effects
  - Extraction Flow
  - Finite DC Gain & DC-Level Offset
  - Settling Response
  - Switch Thermal Noise
- Experimental Results
- Conclusions



# Our Bottom-Up Extraction Flow

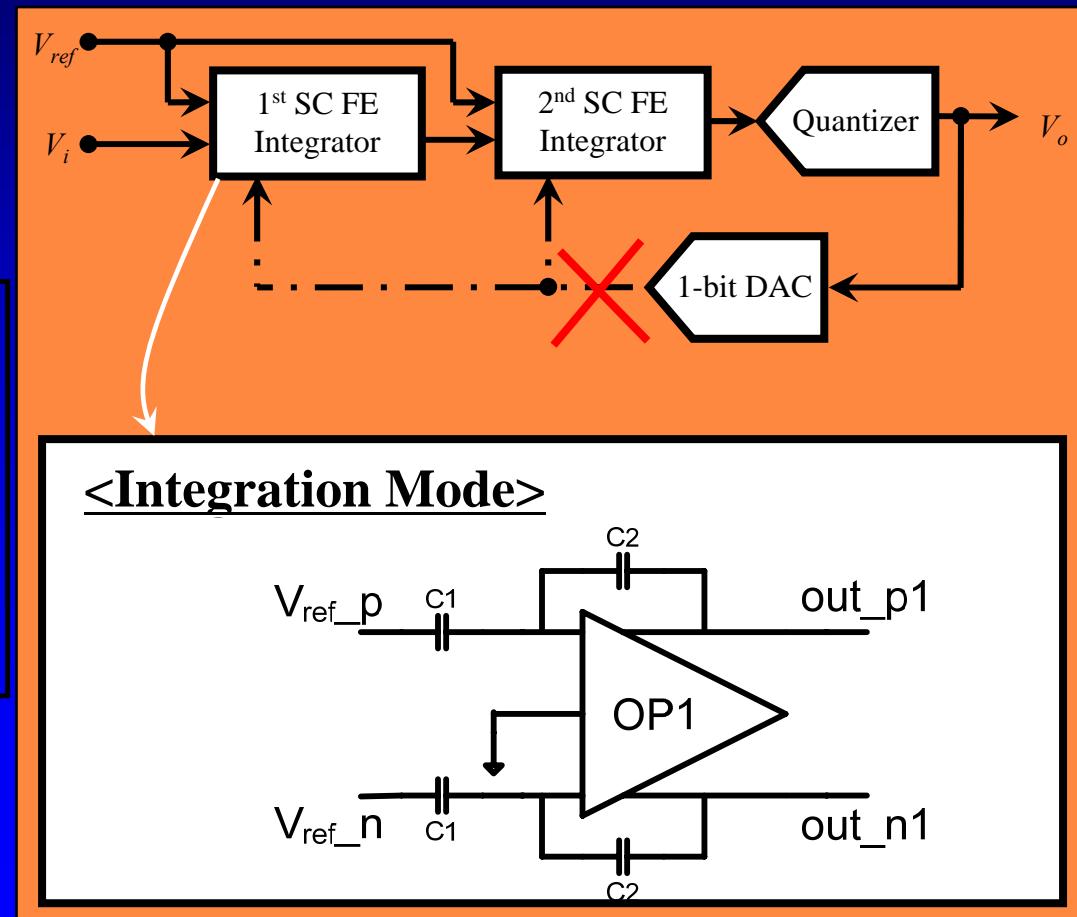
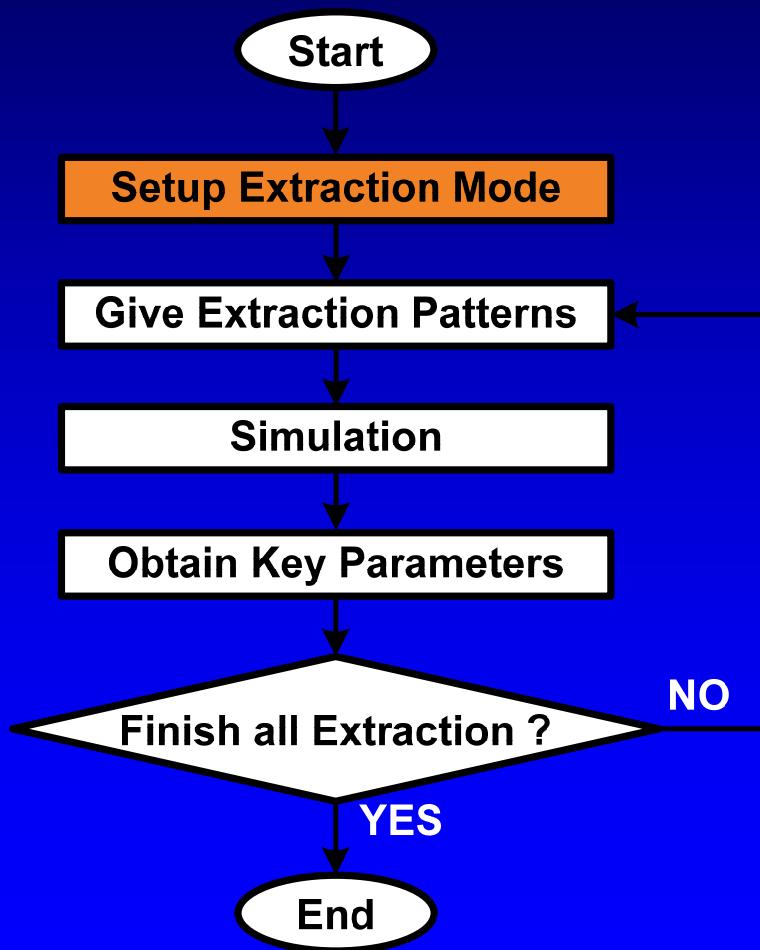
- Execute the bottom-up extraction flow for non-ideal effects





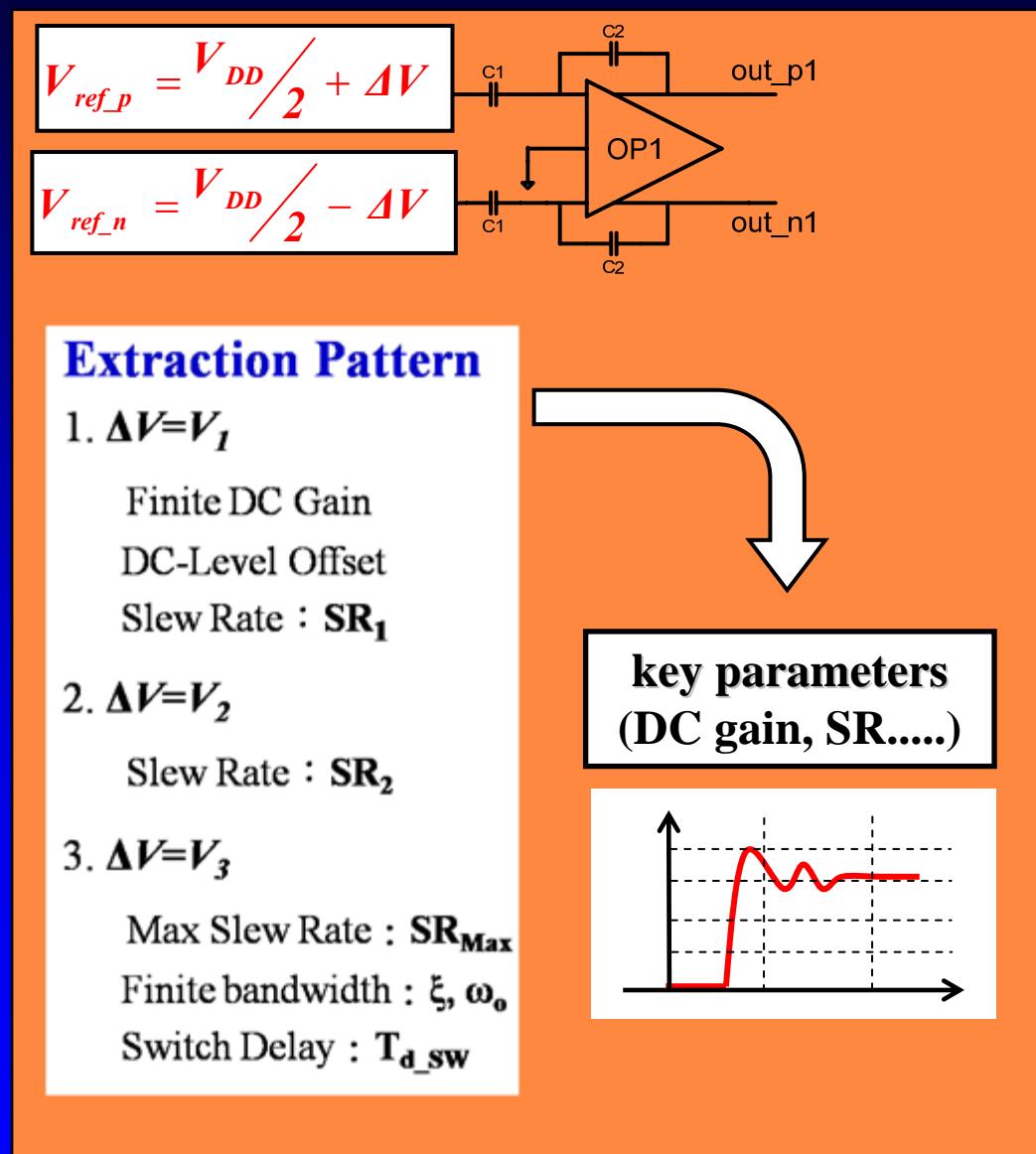
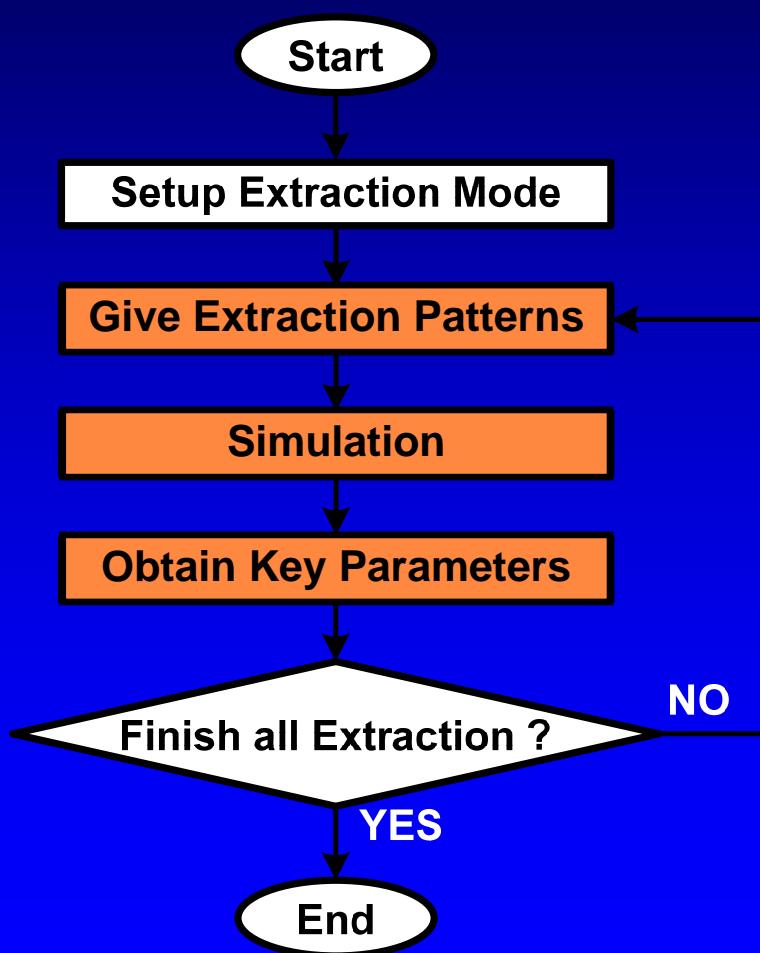
# Extraction Mode

- Break the **feedback loop** of modulator
- Switch SC integrator to **integration mode**





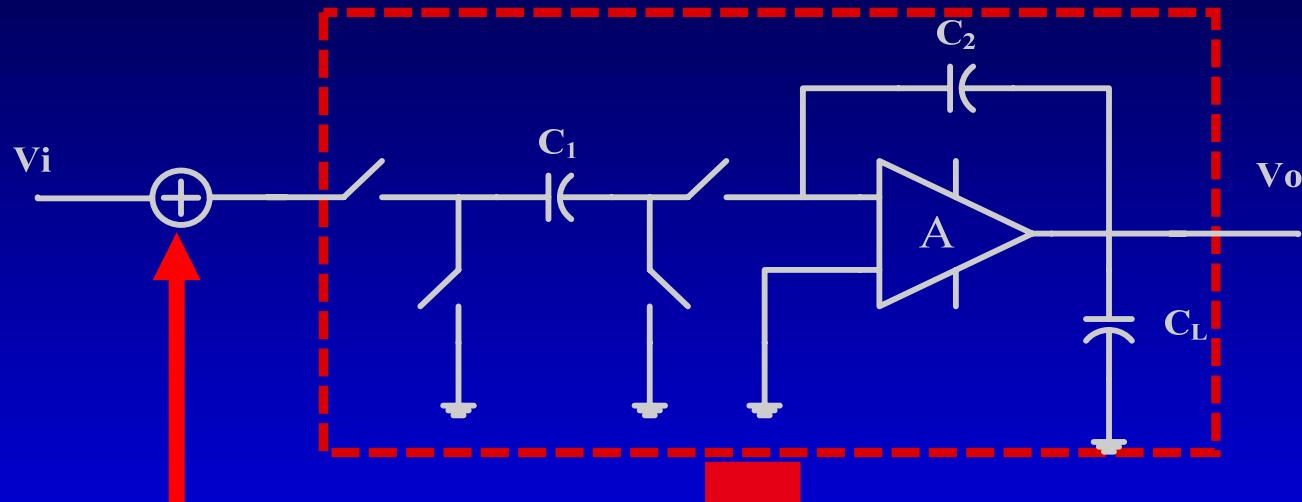
# Extraction Patterns





# Non-Ideal Effects

- SC integrator seriously affects the performance of  $\Delta\Sigma$  modulator



Switch Thermal Noise

Finite DC Gain

+  
Slew Rate

+  
Finite Bandwidth

+  
DC-Level Offset

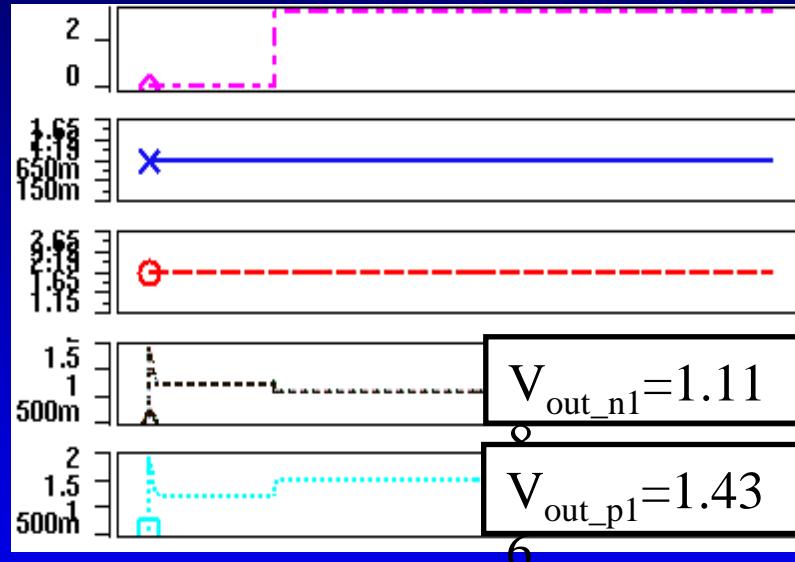
+  
Switch Delay



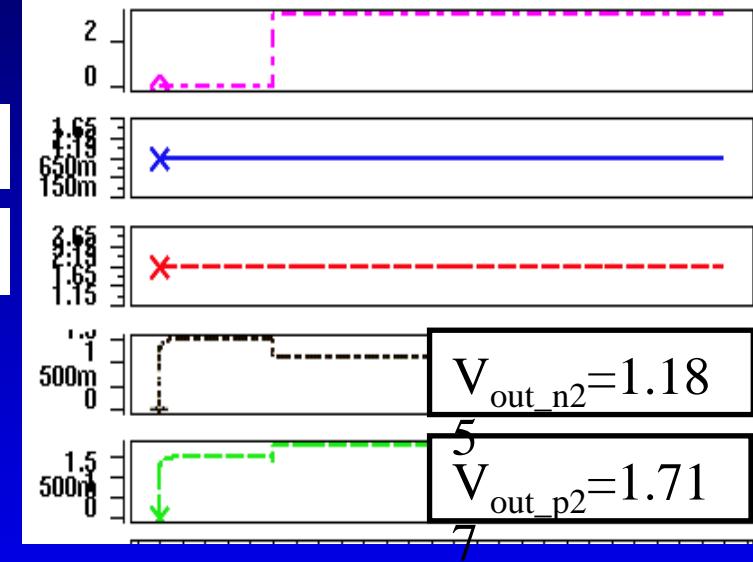
# Extraction – Finite DC Gain

- Extraction patterns :  $V_{ref} = 1.65 \pm 0.4$

1<sup>st</sup> SC Integrator



2<sup>nd</sup> SC Integrator



$$DC\ Gain_{SC1} = \frac{V_{out\_n1} - V_{out\_p1}}{V_{ref\_p} - V_{ref\_n}}$$

$$= \frac{(1.118 - 1.436)}{2.05 - 1.25} = -0.398$$

$$DC\ Gain_{SC2} = \frac{V_{out\_n2} - V_{out\_p2}}{V_{ref\_p} - V_{ref\_n}}$$

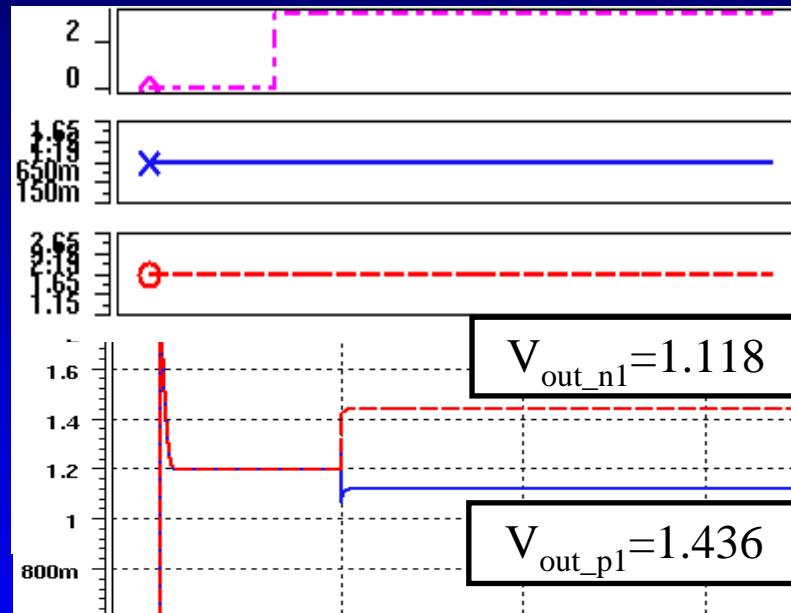
$$= \frac{(1.185 - 1.717)}{2.05 - 1.25} = -0.665$$



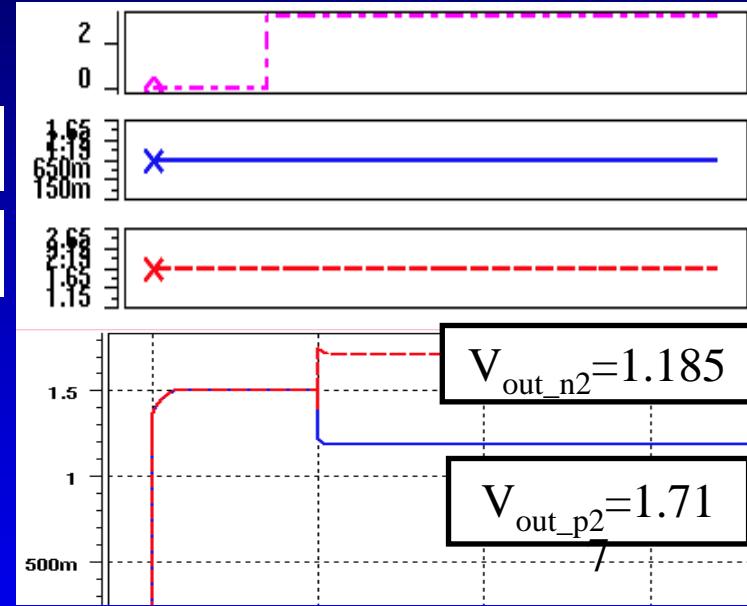
# Extraction – DC-Level Offset

- Extraction patterns :  $V_{ref} = 1.65 \pm 0.4$

1<sup>st</sup> SC Integrator



2<sup>nd</sup> SC Integrator



$$V_{offset} = \frac{V_{DD}}{2} - \frac{V_{out\_n} + V_{out\_p}}{2}$$

$$= \frac{3.3}{2} - \frac{1.118 + 1.436}{2} = 0.373$$

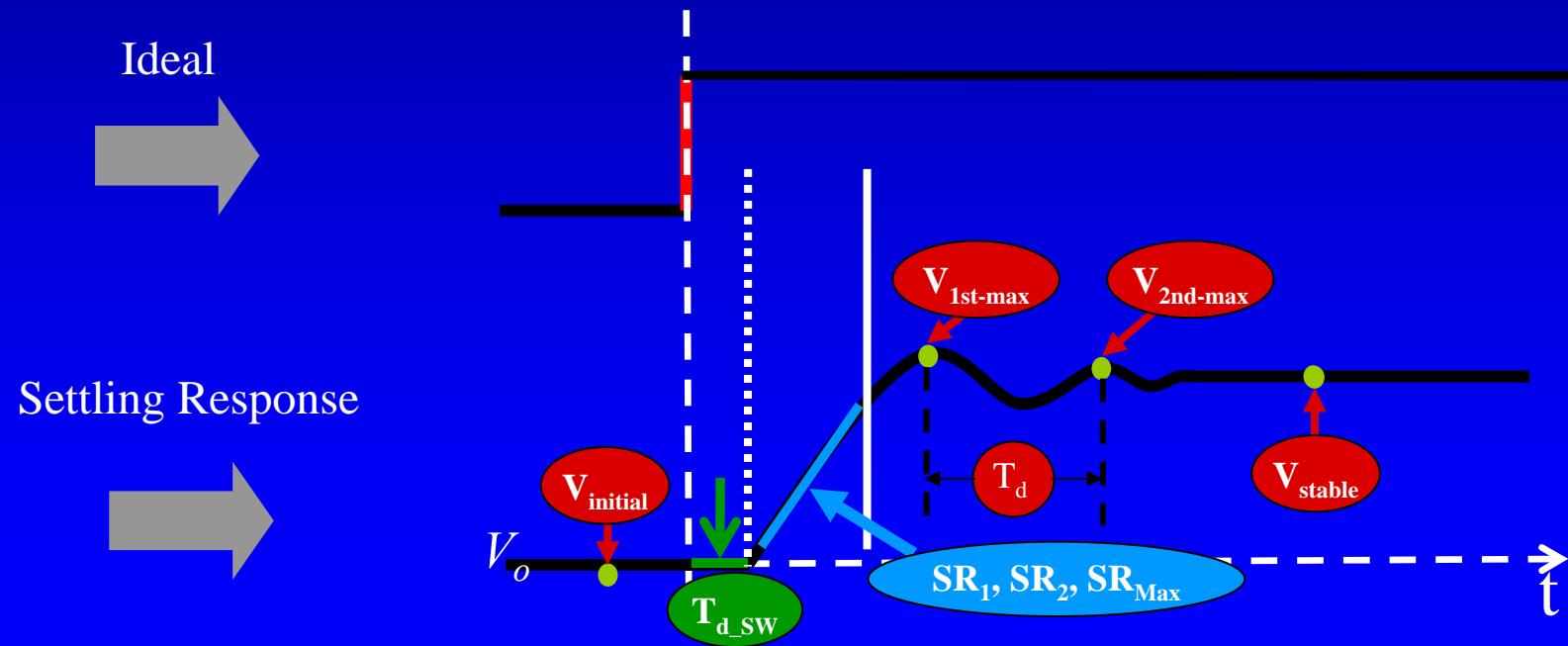
$$V_{offset} = \frac{V_{DD}}{2} - \frac{V_{out\_n} + V_{out\_p}}{2}$$

$$= \frac{3.3}{2} - \frac{1.185 + 1.717}{2} = 0.199$$



# Settling Response

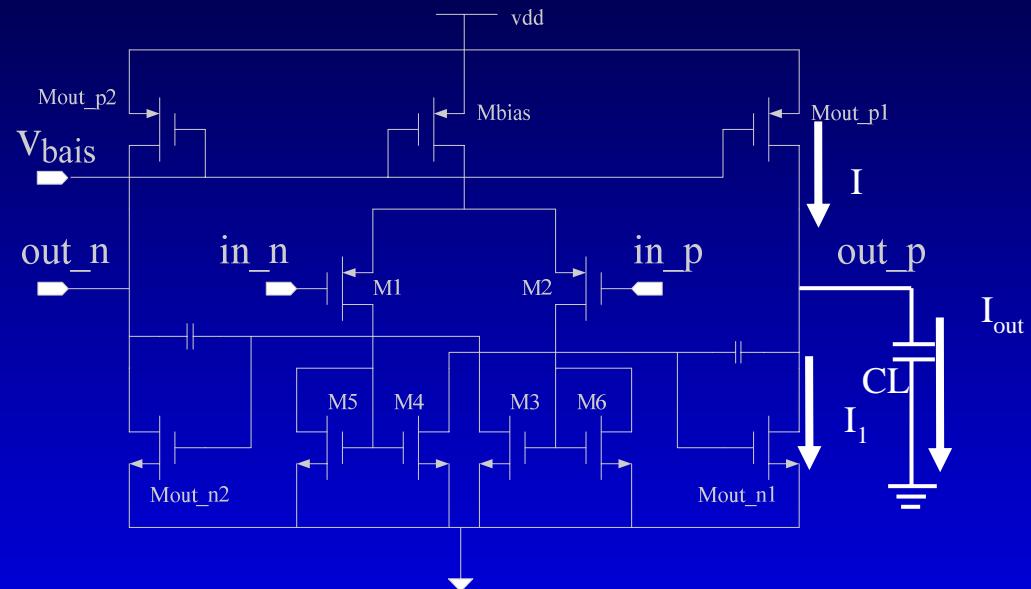
- Include switch delay, finite slew rate ( SR ) and output damping
- Two extraction patterns
  - Obtain two real SR value
- One extraction pattern
  - Obtain output damping, switch delay and Max. SR





# Slew Rate

## □ SR basic formula



$$SR = \frac{I_{out}}{C_L} = \frac{I - I_1}{C_L}$$

$$= \frac{I - \frac{1}{2}\beta(V_{in} - V_{tp} - V_{tn})^2}{C_L}$$

$$V_{ref1} \Rightarrow SR_1 = \frac{I - \frac{1}{2}\beta(V_{ref1} - V_{tp} - V_{tn})^2}{C}$$

$$V_{ref2} \Rightarrow SR_2 = \frac{I - \frac{1}{2}\beta(V_{ref2} - V_{tp} - V_{tn})^2}{C}$$

$$V_{ref} \Rightarrow SR = \frac{I - \frac{1}{2}\beta(V_{ref} - V_{tp} - V_{tn})^2}{C}$$

## □ Dynamic SR calculation equation

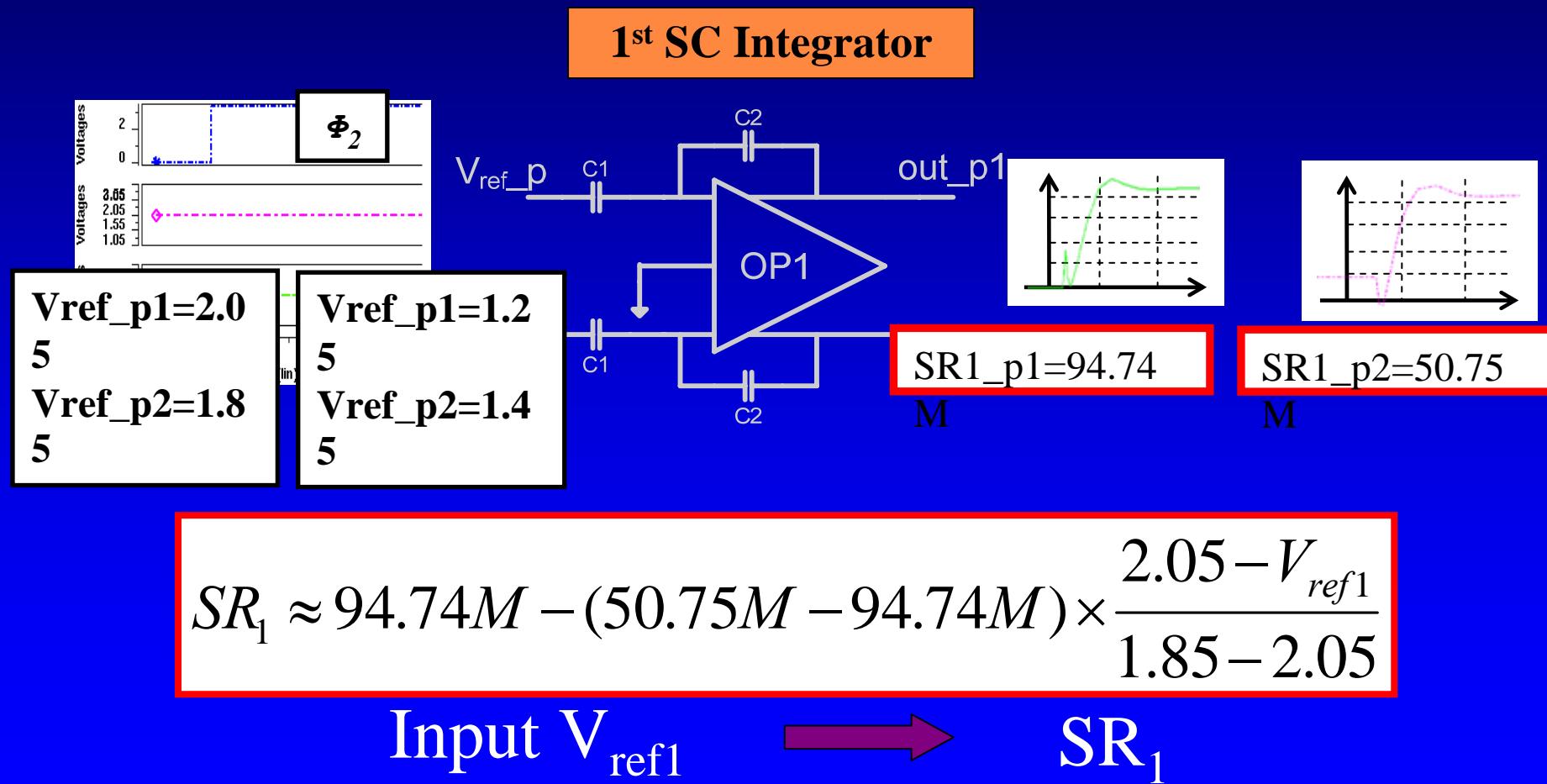
$$\frac{SR_1 - SR_2}{SR_2 - SR_{in}} \approx \frac{V_{ref1} - V_{ref2}}{V_{ref2} - V_{in}} \Rightarrow SR_{in} \approx SR_2 - \frac{V_{ref2} - V_{in}}{V_{ref1} - V_{ref2}} \times (SR_1 - SR_2)$$

( $V_{ref1}, V_{ref2}$  : Extraction Pattern,  $SR_1, SR_2$  : Extraction Value)



# Extraction – SR

- Extraction patterns :  $V_{ref} = 1.65 \pm 0.4 / 1.65 \pm 0.2$



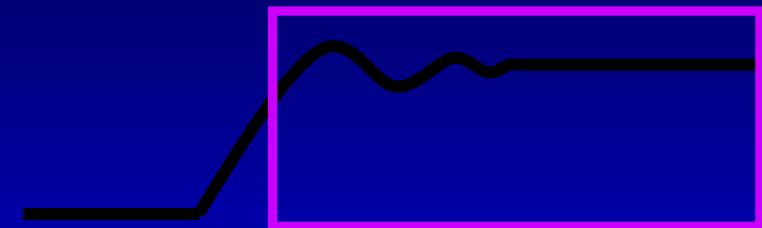


# Output Damping ( 1/2 )

- Second-Order Integrator Transfer Function

$$\frac{V_o(s)}{V_i(s)} = \frac{C_1/C_2 \cdot \omega_o^2}{s^2 + 2\xi\omega_o s + \omega_o^2}$$

Finite bandwidth effect



- Hard to obtain damping ratio (  $\xi$  ) and pole frequency (  $\omega_o$  )

$$\xi = \frac{1}{2 \cdot \sqrt{\left( -\pi / \ln(OS\%) \right)^2 + 4}} \quad iA\omega_o = \frac{2\pi}{T_d \sqrt{1 - \xi^2}}$$

- How to obtain overshoot percent (OS%) and period oscillation ( $T_d$ )
  - Easier to be measured from the output waveform

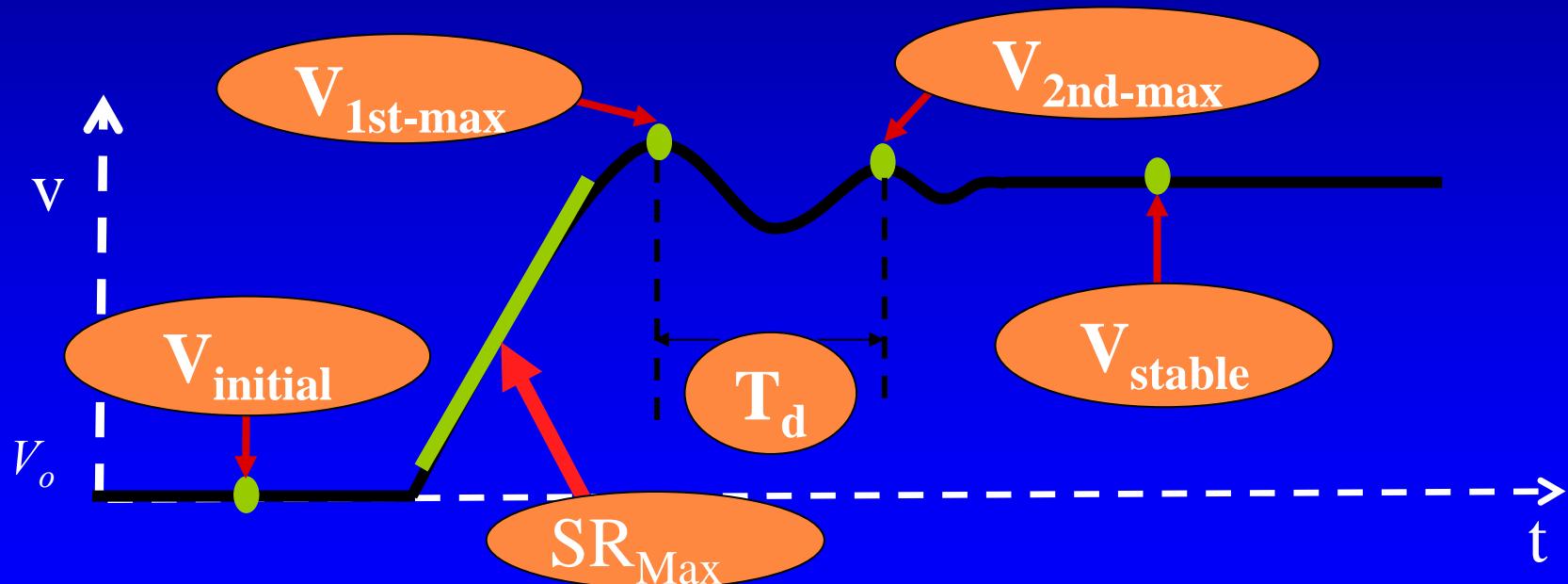
Ref □ P. E. Allen, D. R. Holberg "CMOS Analog Circuit Design" 2nd ed. New York Oxford, 2002



# Output Damping ( 2/2 )

- Obtain overshoot percent ( OS% ), period oscillation (  $T_d$  ) and Max. slew rate (  $SR_{Max}$  ) using one extraction pattern

$$OS \% = \left( \frac{V_{max} - V_{stable}}{V_{stable} - V_{initial}} \right) \cdot 100\% \quad ; \quad AV_{max} = V_{1st-max} - V_{stable}$$



Ref P. E. Allen, D. R. Holberg "CMOS Analog Circuit Design" 2nd ed. New York Oxford, 2002



# Extraction – Output Damping

- Extraction patterns :  $V_{ref} = 1.65 \pm 0.5$

## 1<sup>st</sup> SC Integrator

$$V_{initial} = 1.3921(v), V_{max} = 1.6052(v)$$

$$V_{stable} = 1.5808(v), T_d = 5 \times 10^{-9}(s)$$

$$SR_{Max} = 113.08M$$

$$OS\% = \left( \frac{V_{max} - V_{stable}}{V_{stable} - V_{initial}} \right) = \frac{1.6052 - 1.5808}{1.5808 - 1.3921} = 0.1293$$

$$\xi = \frac{1}{2 \cdot \sqrt{\frac{\left( -\pi / \ln(OS\%) \right)^2 + 1}{4}}} \approx 0.6$$

$$\omega_0 = \frac{2\pi}{T_d \sqrt{1 - \xi^2}} \approx 1.5 \times 10^9$$

## 2<sup>nd</sup> SC Integrator

$$V_{initial} = 1.5012(v), V_{max} = 1.81(v)$$

$$V_{stable} = 1.7741(v), T_d = 0.772 \times 10^{-6}(s)$$

$$SR_{Max} = 19.56M$$

$$OS\% = \left( \frac{V_{max} - V_{stable}}{V_{stable} - V_{initial}} \right) = \frac{1.81 - 1.7741}{1.7741 - 1.5012} = 0.1316$$

$$\xi = \frac{1}{2 \cdot \sqrt{\frac{\left( -\pi / \ln(OS\%) \right)^2 + 1}{4}}} \approx 0.6$$

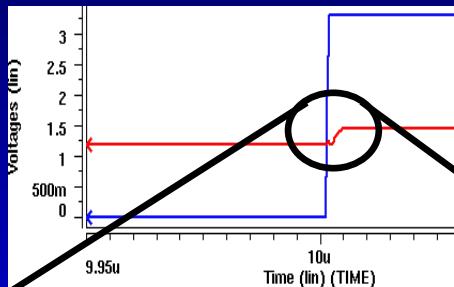
$$\omega_0 = \frac{2\pi}{T_d \sqrt{1 - \xi^2}} \approx 1.02 \times 10^7$$



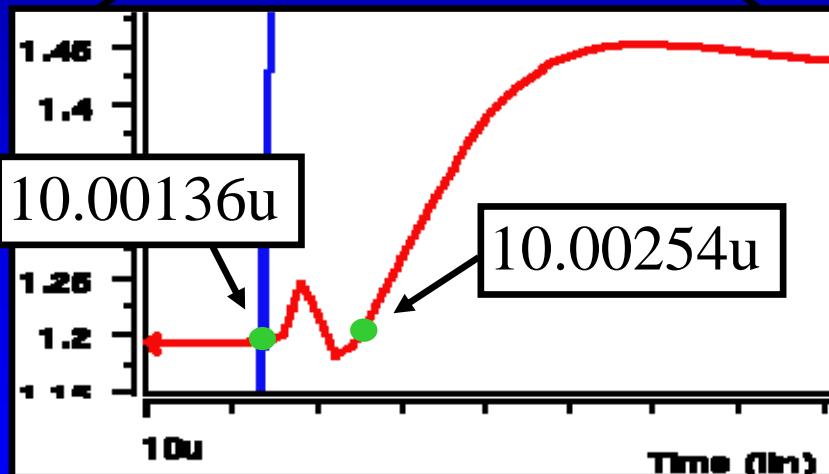
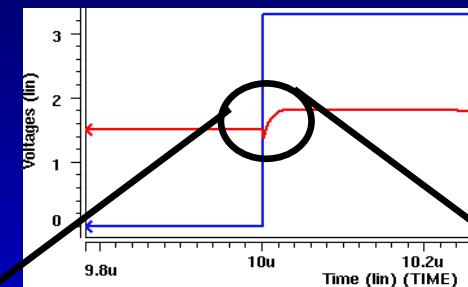
# Extraction – Switch Delay

- Extraction patterns :  $V_{ref} = 1.65 \pm 0.5$

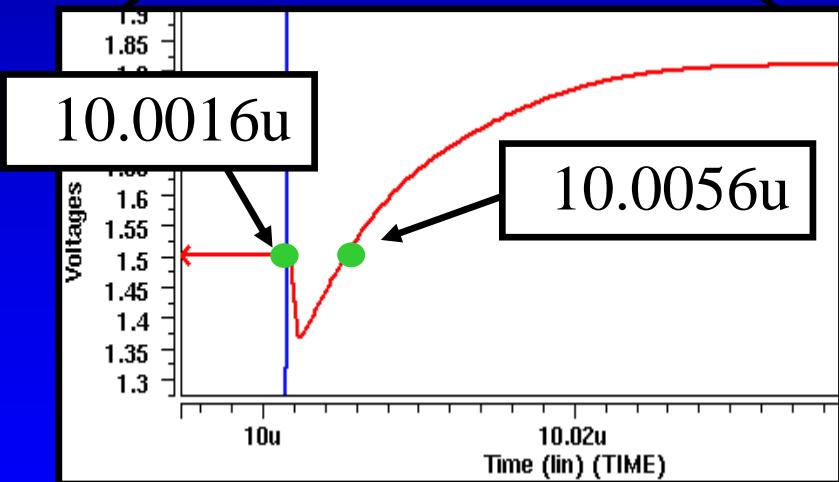
1<sup>st</sup> SC Integrator



2<sup>nd</sup> SC Integrator



$$T_{d\_SW} = 1.18n$$

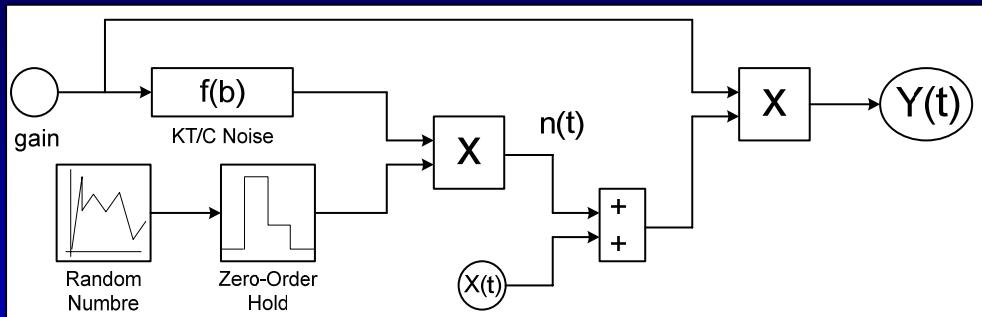


$$T_{d\_SW} = 4n$$



# Switch Thermal Noise

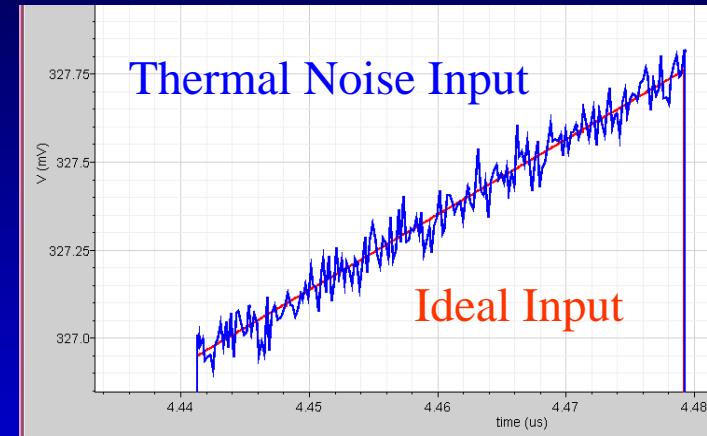
## □ Gaussian random variable



$$e_T^2 = \int_0^\infty \frac{4kTR_{on}}{1 + (2\pi 2\pi_{on} C_s)^2} df = \frac{kT}{C_s}$$

$$V_o(t) = [V_i(t) + e_T(t)] \times DC\ Gain$$

$$V_o(t) = \left[ V_i(t) + \sqrt{\frac{kT}{Cs} \cdot n(t)} \right] \times DC\ Gain$$



$n(t)$ : Gaussian random process with  $\mu=0, \sigma=1$

Ref □ P.Malcovati ,S.Brigati, F.Francesconi, F.Maloberti, P.Cusinato, A.Baschirotto, "Behavioral modeling of switched-capacitor sigma-delta modulators", IEEE TRANSACTIONS ON CIRCUITS AND SYSTEMS I :Fundamental Theory and Applications, VOL. 50, NO. 3, MARCH 2003



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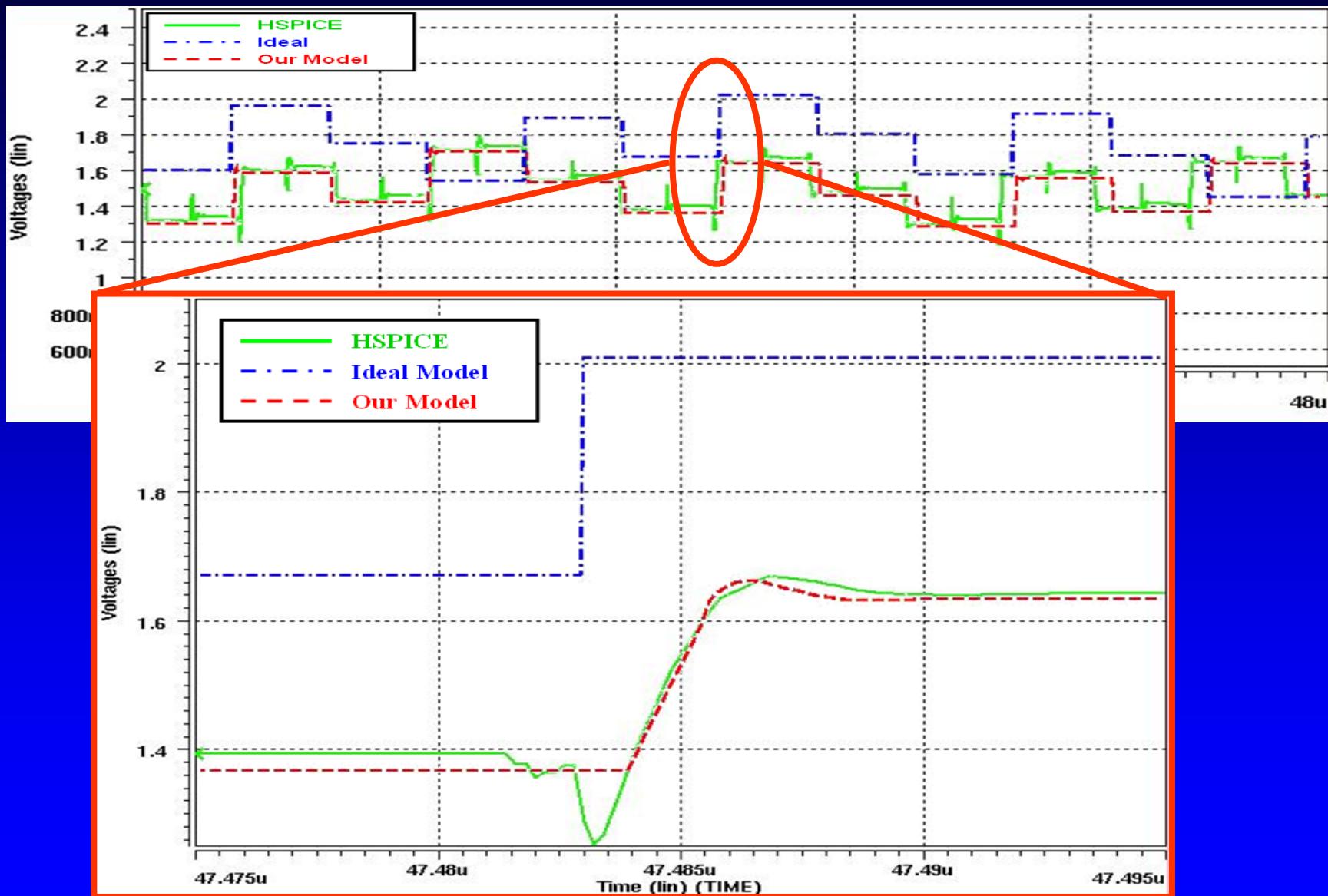


# Setup Environment

- Second-order  $\Delta\Sigma$  modulator
  - Implement in TSMC 0.25um TT\_3V CMOS process
  - Oversampling ratio (OSR) = 303
  - Sampling frequency = 12.5MHz
  - Signal frequency = 20.6 KHz
- Our developed behavioral model
  - Verilog-A language
  - Simulated in Analog Artist (Cadence) using Spectre
- Use “ wavescan ” tool to
  - Show the timing and frequency waveform
  - Calculate Fast Fourier Transform (FFT) and Signal-to-Noise Ratio (SNR)
- FFT & SNR setup parameters
  - Timing range : 800 ns ~ 2622.24 us
  - Signal range : 19.073 KHz ~ 21.362 KHz
  - Noise range : 1.5259 KHz ~ 40.054 KHz
  - Sampling point : 32768

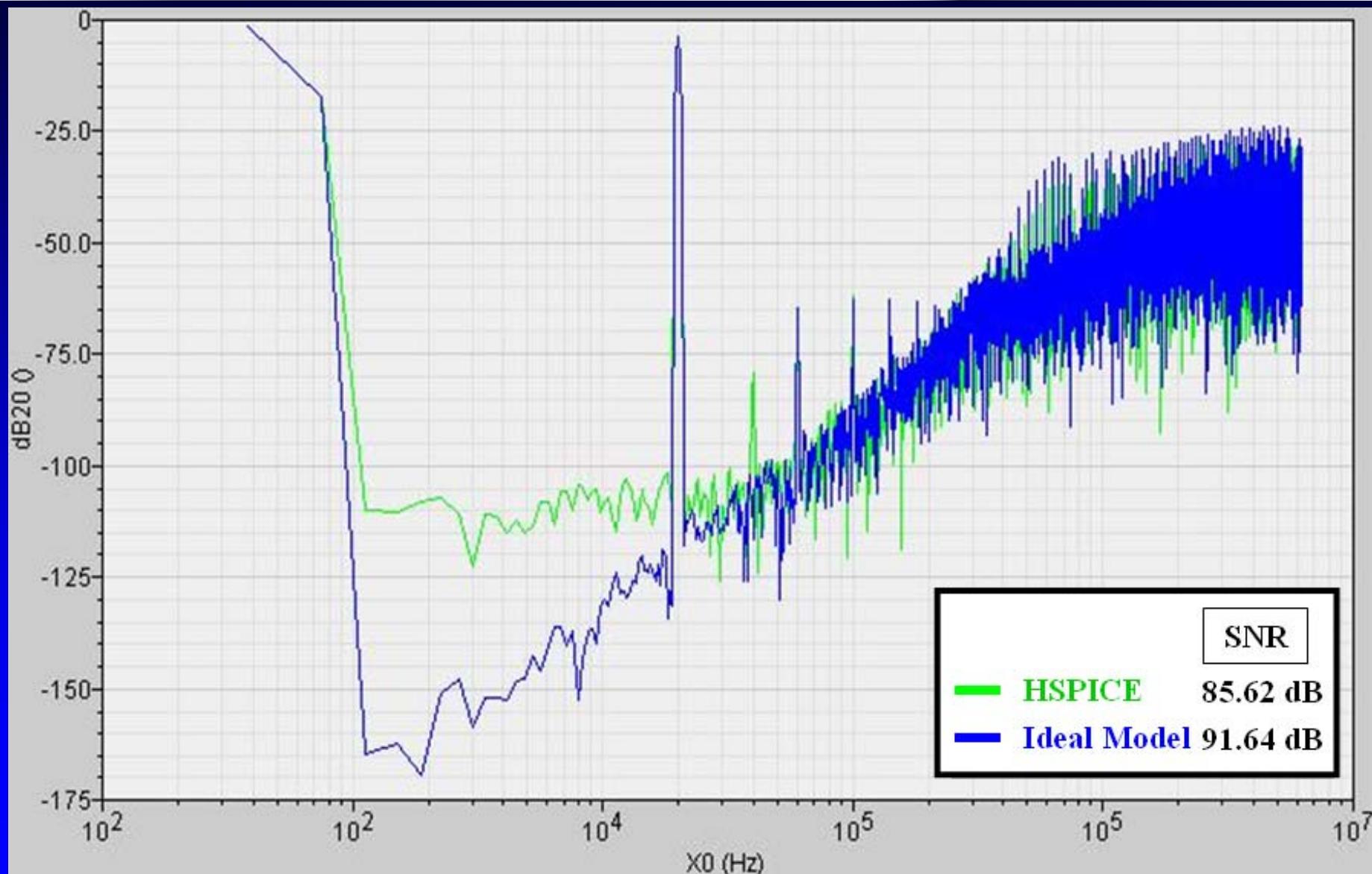


# Timing Waveform



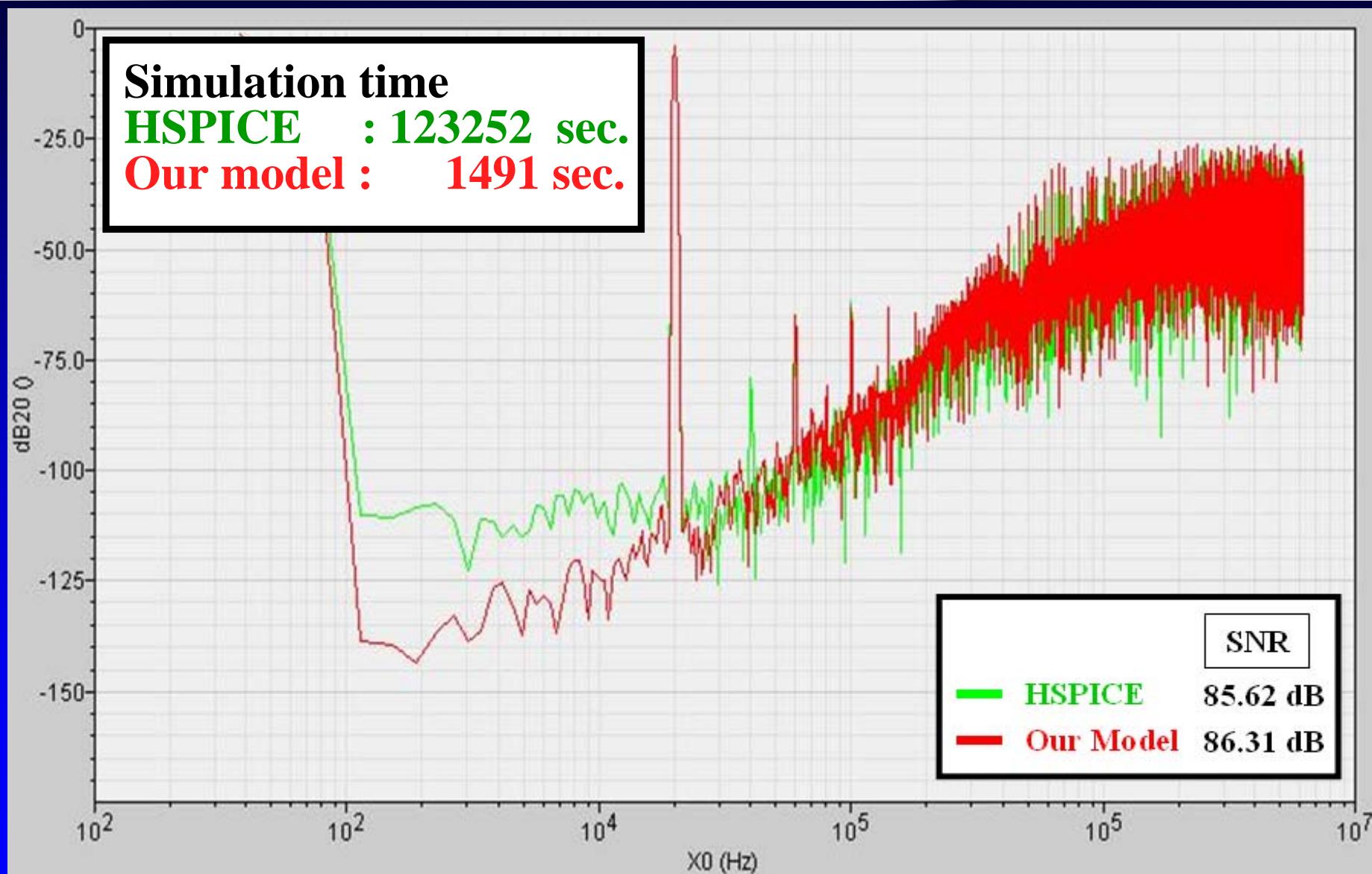


# FFT & SNR ( HSPICE VS Ideal )





# FFT & SNR ( HSPICE VS Our )





# Conclusions

- Our bottom-up extraction approach is suitable for IP-based design
- Switch to extraction mode instead of separating into several sub-blocks
  - Actual loading effects and parasites can be considered automatically
  - Non-ideal effects can be extracted easily using some extraction patterns
- Can include the following non-ideal effects
  - Finite DC gain & DC-level offset
  - Settling response
  - Thermal noise
- Our model is very close to HSPICE results with less simulation time.



# Thanks for your attention ~